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	APPLICATION NO.	FILING DATE	FIRST NAMED IN	/ENTOR	,	ATTORNEY DOCKET NO.
	09/320,27	1 05/27/	99 WATANABE		Н	990559
Г	023850		MM21/0605	$\neg$	EXAMINER	
		, WESTERMAN			LEE, C	• •
	MCLELAND & NAUGHTON, LLP				ART UNIT	PAPER NUMBER
	1725 K STREET, NW, SUITE 1000 WASHINGTON DC 20006		SUITE 1000		2825	
					DATE MAILED:	06/05/01

Please find below and/or attached an Office communication concerning this application or proceeding.

Commissioner of Patents and Trad marks

# 0

## Office Action Summary

Application No. 09/320,271

Applicant(s)

H. WATANABE et al.

Examiner

Calvin Lee

Art Unit 2825

- The MAILING DATE of this communication appe	ars on the cover sheet with the correspondenc address					
Period for Reply	•					
A SHORTENED STATUTORY PERIOD FOR REPLY IS THE MAILING DATE OF THIS COMMUNICATION.	SET TO EXPIRE 3 MONTH(S) FROM					
<ul> <li>Extensions of time may be available under the provisions of 37 CFR after SIX (6) MONTHS from the mailing date of this communicati</li> <li>If the period for reply specified above is less than thirty (30) days, a be considered timely.</li> </ul>	on. reply within the statutory minimum of thirty (30) days will					
communication.	riod will apply and will expire SIX (6) MONTHS from the mailing date of this tute, cause the application to become ABANDONED (35 U.S.C. § 133). ailing date of this communication, even if timely filed, may reduce any					
Status						
1) X Responsive to communication(s) filed on <u>May 14</u>	4, 2001 (CPA and Pre Amendment)					
2a) ☑ This action is <b>FINAL</b> . 2b) 🗷 This a	action is non-final.					
3) Since this application is in condition for allowance except for formal matters, prosecution as to the merits is closed in accordance with the practice under Ex parte Quay/1835 C.D. 11; 453 O.G. 213.						
Disposition of Claims						
4) 🔀 Claim(s) <u>1-13</u>	is/are pending in the applica					
4a) Of the above, claim(s)	is/are withdrawn from considera					
5)	is/are allowed.					
6) 🗓 Claim(s) <u>1-13</u>	is/are rejected.					
7)	is/are objected to.					
8)	are subject to restriction and/or election requirem					
Application Papers	•					
9) The specification is objected to by the Examiner.						
10) The drawing(s) filed oni	s/are objected to by the Examiner.					
11) ☐ The proposed drawing correction filed on	is: a∑ approved b) ☐ disapproved.					
12) ☐ The oath or declaration is objected to by the Exam						
Priority under 35 U.S.C. § 119						
13) 🔀 Acknowledgement is made of a claim for foreign p	priority under 35 U.S.C. § 119(a)-(d).					
a)⊠ All b) ☐ Some* c) ☐None of:						
<ol> <li>Certified copies of the priority documents had</li> </ol>	ve been received.					
2. Certified copies of the priority documents have been received in Application No.						
<ol> <li>Copies of the certified copies of the priority of application from the International Bure</li> <li>*See the attached detailed Office action for a list of the certified of the company of the certified copies of the priority of the certified copies of the c</li></ol>						
14) Acknowledgement is made of a claim for domestic						
Attachment(s)						
15) Notice of References Cited (PTO-892)	18) Interview Summary (PTO-413) Paper No(s).					
16) Notice of Draftsperson's Patent Drawing Review (PTO-948)	19) Notice of Informal Patent Application (PTO-152)					
17) Information Disclosure Statement(s) (PTO-1449) Paper No(s).	20)					

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#### OFFICE ACTION

## Response to Pre Amendment

The amendment of claim 1 in paper 11, filed on May 14, 2001, is acknowledged. 1.

### Claim Rejections - 35. USC § 102 at 11 a flat partie 100 flat parties 100

The following is a quotation of the appropriate paragraphs of 35 U.S.C. 102 that form the 2. basis for the rejections under this section made in this Office action:

A person shall be entitled to a patent unless -- ... it a hoperate the base of the state of the

- (e) the invention was described in a patent granted on an application for patent by another filed in the United States before the invention thereof by the applicant for patent, or on an international application by another who has fulfilled the requirements of paragraphs (1), (2), and (4) of section 371@ of this title before the invention and the section 3710 of this title before the invention. thereof by the applicant for patent.
- 3. Claims 1-13 are rejected under 35 U.S.C. 102(e) as being anticipated by Mizuhara et al. ofarmine a cominci hole 10 milas manistrum iever semp THE STATE OF (US 5,898,221) and/or Watanabe et al. (US 6,017,807).
- Mizuhara discloses a semiconductor device and its method, comprising the steps of: a)
- forming an organic SOG layer 9 as a first insulator, having substantially uniform thickness, on an third and fourth interconnections, as required. oxide film 8 and over a flat substrate's face (Figs. 4-5 and col. 4, lines 25-43)
- <u>Response to Arguments</u> - introducing impurities B<sup>+</sup> into the organic SOG layer (so the impurities arrive at the interface between the SOG layer and its underlying oxide), thereby modifying the organic SOG layer 9 to an SOG layer 10 (Fig. 6 and col. 4, lines 45-51)
- embedding and forming a first conductive layer 13 of copper alloy over a contact hole 12 in the modified SOG layer using a mask pattern (Fig. 8 and col. 4, lines 58-67)

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The method can extends to have second, third, and fourth interconnections, as desired, by repeating the above steps (col. 5 line 61 trough col. 6 line 62).

- b) Watanabe teaches a fabrication method of a semiconductor device, comprising the steps:
- forming a first insulating layer 8 of organic SOG, containing 1% of carbon, on an oxide film 5;
  and overlying a substrate 1 (col. 5 line 17 through col. 6 line 30)
- introducing impurities into the insulating layer (Fig. 4) so the impurities arrive at the interface between the insulating layer and the oxide film (col. 6, line 39 and col. 7, line 32).

  Note: the implantation at the interface between organic SOG layer 8 and oxide film 5 prevents (703) 308-1323.

modified SOG layer 9 (col. 6, line 53) from being easily peeled off from the oxide film (col. 6, soff this application

lines 52-59 and col. 7, lines 30-37)

- forming a contact hole 10 in the insulation layer-using a mask pattern (col. 8 lines 52-63)
- embedding and forming a first conductive layer 11 over-the hole (Fig. 5 and col. 7 lines 9-29)

The method can be repeated to form a conventional multilayer structure having second, third, and fourth interconnections, as required.

### Response to Arguments

The claim rejections under 35 USC § 103 in the last Office Action have been withdrawn. However, claims 1-13 are now rejected under 35 USC § 102(e), whereas the specific portions of *Mizuhara* and *Watanabe*, relied upon by the Examiner to reject the claims, have been pointed out in details in the new rejections above.

Applicant's argument that "Applicant can be his own lexicographer" is generally correct.

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While Applicant may be his own lexicographer, a term "third mask" in a claim may not be used unless first and second masks are previously recited.

In short, Applicant should not use definition in a misleading manner (out of ordinary use).

#### Conclusion

5. Any inquiry concerning this communication from the Examiner should be directed to Calvin Lee at (703) 306-5854 from 7:00AM to 5:00PM (Monday through Thursday). If attempts to reach the examiner by telephone are unsuccessful, Art Unit 2825's Supervisory Patent Examiner Matthew Smith whose telephone number is (703) 308-1323.

Any inquiry of a general nature or relating to the status of this application or proceeding should be directed to the Group receptionist whose telephone number is (703) 308-0956 or (703) 306-3329.

CL

May 29, 2001

MATTHEW SMITH

Wareh Som

SUPERVISORY PATENT EXAMINER

Cartallogy CENTER 2800